



## FORM PTO-1449

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Mervyn J. Miles et al.FILING DATE  
07/02/2003GROUP  
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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/TXL/	AA	3,702,398	11/1972	Van-Essen et al.	250	310	
/TXL/	AB	5,412,980	05/1995	Elings et al.	73	105	
/TXL/	AC	5,566,159	10/1996	Shapira	369	124 .02	
/TXL/	AD	6,094,971	08/2000	Edwards et al.	73	105	
/TXL/	AE	6,236,783	05/2001	Mononobe et al.	385	43	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
/TXL/	AI	0 8 6 4 8 9 9	9/1998	Europe				
/TXL/	AF	5 4 5 5 3 8 A1	09/2003	Europe				
	AG	1 0 5 0 1 4 66	10/1996	Germany				
	AH	1 0 0 5 2 8 33	5/2000	Germany				
/TXL/	AJ	2 0 0 1 4 5 19	1/2001	Japan				X*
/TXL/	AK	2 0 0 0 19 97 36	7/2000	Japan				X*

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

/TXL/	AL	M. Antognozzi, et al., A New Method To Measure The Oscillation Of A Cylindrical Cantilever: "The Laser Reflection Detection System," 04/2000, Review of Scientific Instruments, Volume 71, No. 4, pp 1689-1694
/TXL/	AM	S.K. Sekatskii, et al., Time-Gated Scanning Near-Field Optical Microscopy, 10/2/2000, Applied Physics Letters, Volume 77, No. 14, pp 2089-2091
/TXL/	AN	S.H. Simpson, et al., Analysis Of The Effect Arising From The Near-Field Optical Microscopy Of Homogeneous Dielectric Slabs, 09/1/2001, Optics Communications 196, pp 17-31
/TXL/	AO	Khaled Karrai, et al., Piezoelectric tip-sample control for near field optical microscopes, 04/3/1995, American Institute of Physics, Vol. 66, No. 14, pp 1842-1844
/TXL/	AP	Claire E. Jordan, et al., Removing optical artifacts in near-field scanning optical microscopy by using a three-dimensional scanning mode, 09/1/1999, Journal of Applied Physics, Vol. 86, No. 5, pp 2785-2789
	AQ	Oshikane et al., Scanning Near-Field Optical Microscope With A Small Spherical Protrusion Probe Excited With WGM Resonances, Optical Memory & Neural Networks 2000, Vol. 9, No. 3, pp 147-160
/TXL/	AR	Oshikane et al., 3D-FDTD and experimental analysis of a resonant microcavity probe for high-resolution SNOM, Physics Devices & Information Processing, 07/1999, Vol. 3791, pp 57-62

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/Thanh X Luu/DATE CONSIDERED  
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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